

Search Notes

Application/Control No.

10/526,461

Examiner

Bin Shen

Applicant(s)/Patent under
Reexamination

KAUPPI ET AL.

Art Unit

1657

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STIC search see eDAN.	3/30/2007	BS